www.ti.com

FLATLINK™ TRANSMITTER

Check for Samples: SN75LVDS83B

FEATURES

- LVDS Display Serdes Interfaces Directly to LCD Display Panels with Integrated LVDS
- Package Options: 4.5mm x 7mm BGA, and 8.1mm x 14mm TSSOP
- 1.8V up to 3.3V Tolerant Data Inputs to Connect Directly to Low-Power, Low-Voltage **Application and Graphic Processors**
- Transfer Rate up to 135Mpps (Mega Pixel Per Second); Pixel Clock Frequency Range 10MHz to 135MHz
- Suited for Display Resolutions Ranging From **HVGA up to HD With Low EMI**
- Operates From a Single 3.3V Supply and 170mW (typ.) at 75MHz
- 28 Data Channels Plus Clock In Low-Voltage TTL to 4 Data Channels Plus Clock Out Low-

Voltage Differential

- **Consumes Less Than 1mW When Disabled**
- Selectable Rising or Falling Clock Edge **Triggered Inputs**
- **ESD: 5kV HBM**
- **Support Spread Spectrum Clocking (SSC)**
- Compatible with all OMAP™2x, OMAP™3x, and DaVinci™ Application Processors

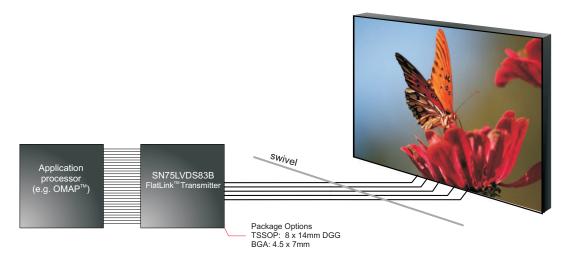
APPLICATIONS

- **LCD Display Panel Driver**
- **UMPC** and Netbook PC
- **Digital Picture Frame**

DESCRIPTION

The SN75LVDS83B FlatLink™ transmitter contains four 7-bit parallel-load serial-out shift registers, a 7X clock synthesizer, and five Low-Voltage Differential Signaling (LVDS) line drivers in a single integrated circuit. These functions allow 28 bits of single-ended LVTTL data to be synchronously transmitted over five balanced-pair conductors for receipt by a compatible receiver, such as the SN75LVDS82 and LCD panels with integrated LVDS receiver.

When transmitting, data bits D0 through D27 are each loaded into registers upon the edge of the input clock signal (CLKIN). The rising or falling edge of the clock can be selected via the clock select (CLKSEL) pin. The frequency of CLKIN is multiplied seven times, and then used to unload the data registers in 7-bit slices and serially. The four serial streams and a phase-locked clock (CLKOUT) are then output to LVDS output drivers. The frequency of CLKOUT is the same as the input clock, CLKIN.





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet. OMAP. DaVinci, FlatLink are trademarks of Texas Instruments.





This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

DESCRIPTION (CONTINUED)

The SN75LVDS83B requires no external components and little or no control. The data bus appears the same at the input to the transmitter and output of the receiver with the data transmission transparent to the user(s). The only user intervention is selecting a clock rising edge by inputting a high level to CLKSEL or a falling edge with a low-level input, and the possible use of the Shutdown/Clear (SHTDN). SHTDN is an active-low input to inhibit the clock, and shut off the LVDS output drivers for lower power consumption. A low-level on this signal clears all internal registers to a low-level.

The SN75LVDS83B is characterized for operation over ambient air temperatures of -10°C to 70°C.

Alternative device option: The SN75LVDS83A (SLLS980) is an alternative to the SN75LVDS83B for clock frequency range of 10MHz-100MHz only. The SN75LVDS83A is available in the TSSOP package option only.

ORDERING INFORMATION(1)

| PART NUMBER | PART MARKING | PACKAGE |
|-----------------|--------------------------|----------------------|
| SN75LVDS83BZQLR | LVDS83B in BGA package | 56-pin ZQL LARGE T&R |
| SN75LVDS83BDGG | LVDS83B in TSSOP package | 56-pin DGG TUBE |
| SN75LVDS83BDGGR | LVDS83B in TSSOP package | 56-pin DGG LARGE T&R |

⁽¹⁾ For the most current package and ordering information, see the Package Option Addendum located at the end of this data sheet, or refer to our web site at www.ti.com.

ABSOLUTE MAXIMUM RATINGS(1)

| | | VALUE | UNIT |
|--|--|------------------------|-------------|
| Supply voltage range, VCC, IOVCC, LVDSVCC, PLLVCC ⁽²⁾ | | -0.5 to 4 | V |
| Voltage range at any output terminal | | -0.5 to VCC + 0.5 | V |
| Voltage range at any input terminal -0.5 to IOVCC + 0.5 | | V | |
| Continuous power dissipation | | See the dissipation ra | ating table |
| Storage temp | erature, T _s | -65 to 150 | °C |
| | Human Body Model (HBM) ⁽³⁾ all pins | 5 | kV |
| ESD rating | Charged Device Model (CDM) ⁽⁴⁾ all pins | 500 | V |
| | Machine Model (MM) ⁽⁵⁾ all pins | 150 | V |

⁽¹⁾ Stresses above these ratings may cause permanent damage. Exposure to absolute maximum conditions for extended periods may degrade device reliability. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those specified is not implied.

- (2) All voltages are with respect to the GND terminals.
- (3) In accordance with JEDEC Standard 22, Test Method A114-A.
- (4) In accordance with JEDEC Standard 22, Test Method C101.
- (5) In accordance with JEDEC Standard 22, Test Method A115-A.

www.ti.com

RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

| PARAMETER | | MIN | NOM | MAX | UNIT | |
|--|--------------|----------------|-----------------|----------------|------|--|
| Supply voltage, VCC | | 3 | 3.3 | 3.6 | | |
| LVDS output Supply voltage, LVDSVCC | | 3 | 3.3 | 3.6 | | |
| PLL analog supply voltage, PLLVCC | | 3 | 3.3 | 3.6 | V | |
| IO input reference supply voltage, IOVCC | | 1.62 | 1.8 / 2.5 / 3.3 | 3.6 | | |
| Power supply noise on any VCC terminal | | | | 0.1 | | |
| | IOVCC = 1.8V | IOVCC/2 + 0.3V | | | | |
| High-level input voltage, V _{IH} | IOVCC = 2.5V | IOVCC/2 + 0.4V | | | V | |
| | IOVCC = 3.3V | IOVCC/2 + 0.5V | | | | |
| | IOVCC = 1.8V | | | IOVCC/2 - 0.3V | | |
| Low-level input voltage, V _{IL} | IOVCC = 2.5V | | | IOVCC/2 - 0.4V | V | |
| | IOVCC = 3.3V | | | IOVCC/2 - 0.5V | | |
| Differential load impedance, Z _L | | 90 | | 132 | Ω | |
| Operating free-air temperature, T _A | | -10 | | 70 | С | |

DISSIPATION RATINGS

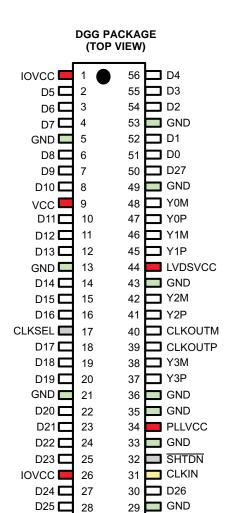
| PACKAGE | CIRCUIT BOARD MODEL(1) | T _{JA} ≤ 25°C | DERATING FACTOR ⁽²⁾ ABOVE T _{JA} = 25°C | T _{JA} = 70°C POWER RATING |
|--------------------|------------------------|------------------------|--|--|
| DGG | Low K | 1111mW | 12.3mW/°C | 555mW |
| ZQL | Low-K | 1034mW | 11.5mW/°C | 517mW |
| DGG ⁽³⁾ | l liab K | 1730mW | 19mW/°C | 865mW |
| ZQL | High-K | 2000mW | 22mW/°C | 1000mW |

- (1) In accordance with the High-K and Low-K thermal metric definitions of EIA/JESD51-2.
- (2) This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.
- (3) DGG junction to case thermal reistance (θ_{JC}) is 15.4°C/W.

TIMING REQUIREMENTS

| UNIT |
|-------|
|) ns |
| · |
| |
| ns |
| ns ns |
| ns |
| ns |
| > |

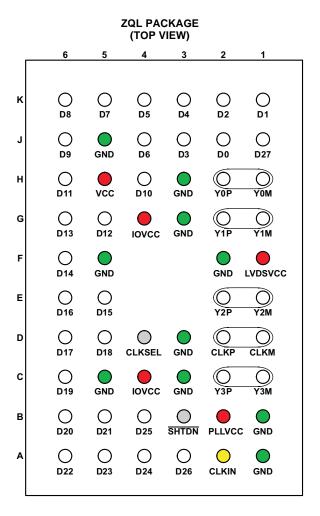




DGG PIN LIST

| Pin # | Signal | Pin # | Signal | Pin # | Signal | Pin # | Signal |
|-------|--------|-------|--------|-------|---------|-------|---------|
| 1 | IOVCC | 15 | D15 | 29 | GND | 43 | GND |
| 2 | D5 | 16 | D16 | 30 | D26 | 44 | LVDSVCC |
| 3 | D6 | 17 | CLKSEL | 31 | CLKIN | 45 | Y1P |
| 4 | D7 | 18 | D17 | 32 | SHTDN | 46 | Y1M |
| 5 | GND | 19 | D18 | 33 | GND | 47 | Y0P |
| 6 | D8 | 20 | D19 | 34 | PLLVCC | 48 | Y0M |
| 7 | D9 | 21 | GND | 35 | GND | 49 | GND |
| 8 | D10 | 22 | D20 | 36 | GND | 50 | D27 |
| 9 | VCC | 23 | D21 | 37 | Y3P | 51 | D0 |
| 10 | D11 | 24 | D22 | 38 | Y3M | 52 | D1 |
| 11 | D12 | 25 | D23 | 39 | CLKOUTP | 53 | GND |
| 12 | D13 | 26 | IOVCC | 40 | CLKOUTM | 54 | D2 |
| 13 | GND | 27 | D24 | 41 | Y2P | 55 | D3 |
| 14 | D14 | 28 | D25 | 42 | Y2M | 56 | D4 |





ZQL PIN LIST

| Ball # | Signal | Ball # | Signal | Ball # | Signal |
|--------|--------------------|--------|--------|--------|--------------------|
| A1 | GND | A2 | CLKIN | A3 | D26 |
| A4 | D24 | A5 | D23 | A6 | D22 |
| B1 | GND | B2 | PLLVCC | B3 | SHTDN |
| B4 | D25 | B5 | D21 | B6 | D20 |
| C1 | Y3M | C2 | Y3P | C3 | GND |
| C4 | IOVCC | C5 | GND | C6 | D19 |
| D1 | CLKM | D2 | CLKP | D3 | GND |
| D4 | CLKSEL | D5 | D18 | D6 | D17 |
| E1 | Y2M | E2 | Y2P | E3 | ball not populated |
| E4 | ball not populated | E5 | D15 | E6 | D16 |
| F1 | LVDSVCC | F2 | GND | F3 | ball not populated |
| F4 | ball not populated | F5 | GND | F6 | D14 |
| G1 | Y1M | G2 | Y1P | G3 | GND |
| G4 | IOVCC | G5 | D12 | G6 | D13 |
| H1 | Y0M | H2 | Y0P | H3 | GND |
| H4 | D10 | H5 | VCC | H6 | D11 |
| J1 | D27 | J2 | D0 | J3 | D3 |
| J4 | D6 | J5 | GND | J6 | D9 |



ZQL PIN LIST (continued)

| K1 | D1 | K2 | D2 | K3 | D4 |
|----|----|----|----|----|----|
| K4 | D5 | K5 | D7 | K6 | D8 |

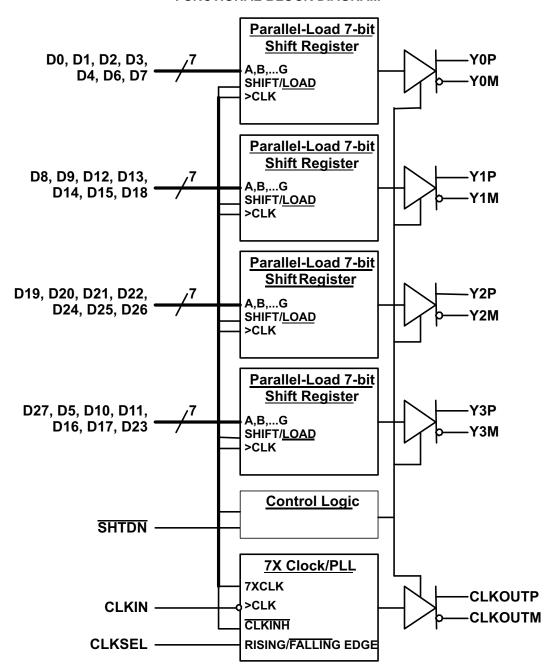
PIN FUNCTIONS

| TERMINAL | I/O | DESCRIPTION |
|---------------------------------|-----------------------------|---|
| Y0P, Y0M, Y1P, Y1M, Y2P, Y2M | | Differential LVDS data outputs. Outputs are high-impedance when SHTDN is pulled low (de-asserted) |
| Y3P, Y3M | LVDS Out | Differential LVDS Data outputs. Output is high-impedance when SHTDN is pulled low (de-asserted). Note: if the application only requires 18-bit color, this output can be left open. |
| CLKP, CLKM | | Differential LVDS pixel clock out <u>put.</u> Output is high-impedance when SHTDN is pulled low (de-asserted). |
| D0 – D27 | CMOS IN with | Data inputs; supports 1.8V to 3.3V input voltage selectable by VDD supply. To connect a graphic source successfully to a display, the bit assignment of D[27:0] is critical (and not necessarily intuitive). For input bit assignment see Figure 14 to Figure 17 for details. Note: if application only requires 18-bit color, connect unused inputs D5, D10, D11, D16, D17, D23, and D27 to GND. |
| CLKIN | pulldn | Input pixel clock; rising or falling clock polarity is selectable by Control input CLKSEL. |
| SHTDN | | Device shut down; pull low (de-assert) to shut down the device (low power, resets all registers) and high (assert) for normal operation. |
| CLKSEL | | Selects between rising edge input clock trigger (CLKSEL = V_{IH}) and falling edge input clock trigger (CLKSEL = V_{IL}). |
| VCC | | 3.3V digital supply voltage |
| IOVCC | | I/O supply reference voltage (1.8V up to 3.3V matching the GPU data output signal swing) |
| PLLVCC | Power Supply ⁽¹⁾ | 3.3V PLL analog supply |
| LVDSVCC | | 3.3V LVDS output analog supply |
| GND | | Supply ground for VCC, IOVCC, LVDSVCC, and PLLVCC. |

⁽¹⁾ For a multilayer pcb, it is recommended to keep one common GND layer underneath the device and connect all ground terminals directly to this plane.



FUNCTIONAL BLOCK DIAGRAM



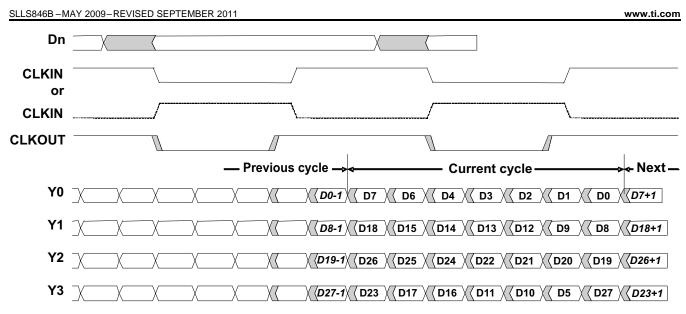


Figure 1. Typical SN75LVDS83B Load and Shift Sequences

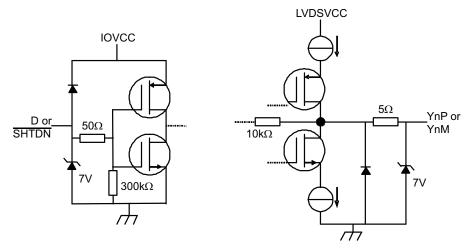


Figure 2. Equivalent Input and Output Schematic Diagrams

www.ti.com

ELECTRICAL CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP ⁽¹⁾ | MAX | UNIT |
|---------------------|---|--|-------|--------------------|-------|------|
| V _T | Input voltage threshold | | | IOVCC/2 | | V |
| V _{OD} | Differential steady-state output voltage magnitude | $R_L = 100\Omega$, See Figure 4 | 250 | | 450 | mV |
| V V _{OD} | Change in the steady-state differential output voltage magnitude between opposite binary states | 11, 2 1001, 000 riguio 1 | | 1 | 35 | mV |
| / _{OC(SS)} | Steady-state common-mode output voltage | See Figure 4 | 1.125 | | 1.375 | V |
| / _{OC(PP)} | Peak-to-peak common-mode output voltage | t _{R/F} (Dx, CLKin) = 1ns | | | 35 | mV |
| Н | High-level input current | V _{IH} = IOVCC | | | 25 | μA |
| L | Low-level input current | V _{IL} = 0 V | | | ±10 | μA |
| | 0 | V _{OY} = 0 V | | | ±24 | mA |
| os | Short-circuit output current | V _{OD} = 0 V | | | ±12 | mA |
| DΖ | High-impedance state output current | V _O = 0 V to VCC | | | ±20 | μA |
| | Input pull-down integrated resistor on all | IOVCC = 1.8V | | 200 | | 1.0 |
| R _{pdn} | inputs (Dx, CLKSEL, SHTDN, CLKIN) | IOVCC = 3.3V | | 100 | | kΩ |
| 2 | Quiescent current (average) | disabled, all inputs at GND; SHTDN = V _{IL} | | 2 | 100 | μA |
| | | $\overline{\text{SHTDN}} = \text{V}_{\text{IH}}, \text{ R}_{\text{L}} = 100\Omega$ (5 places), grayscale pattern (Figure 5) VCC = 3.3V, f _{CLK} = 75MHz | | | | |
| | | I _(VCC) + I _(PLLVCC) + I _(LVDSVCC) | | 51.9 | | |
| | | I _(IOVCC) with IOVCC = 3.3V | | 0.4 | | mA |
| | | I _(IOVCC) with IOVCC = 1.8V | | 0.1 | | |
| | | $\overline{\text{SHTDN}} = \text{V}_{\text{IH}}, \text{ R}_{\text{L}} = 100\Omega \text{ (5 places), 50\%} \\ \text{transition density pattern (Figure 5),} \\ \text{VCC} = 3.3\text{V, } f_{\text{CLK}} = 75\text{MHz}$ | | | | |
| | | I _(VCC) + I _(PLLVCC) + I _(LVDSVCC) | | 53.3 | | |
| | | I _(IOVCC) with IOVCC = 3.3V | | 0.6 | | |
| | | I _(IOVCC) with IOVCC = 1.8V | | 0.2 | | |
| | | $\overline{\text{SHTDN}} = \text{V}_{\text{IH}}, \text{R}_{\text{L}} = 100\Omega (5 \text{places}), \text{worst-case pattern (Figure 6)}, \text{VCC} = 3.6 \text{V}, \text{f}_{\text{CLK}} = 75 \text{MHz}$ | | | | |
| cc | Supply current (average) | I _(VCC) + I _(PLLVCC) + I _(LVDSVCC) | | 63.7 | | |
| | | I _(IOVCC) with IOVCC = 3.3V | | 1.3 | | mA |
| | | I _(IOVCC) with IOVCC = 1.8V | | 0.5 | | |
| | | $\overline{\text{SHTDN}} = \text{V}_{\text{IH}}, \text{R}_{\text{L}} = 100\Omega \text{(5 places), worst-case pattern (Figure 6),} \\ \text{f}_{\text{CLK}} = 100\text{MHz}$ | | | 1 | |
| | | I _(VCC) + I _(PLLVCC) + I _(LVDSVCC) | | 81.6 | | |
| | | I _(IOVCC) with IOVCC = 3.6V | | 1.6 | | mA |
| | | I _(IOVCC) with IOVCC = 1.8V | | 0.6 | | |
| | | $\label{eq:shtdn} \hline \textbf{SHTDN} = \textbf{V}_{\text{IH}}, \textbf{R}_{\text{L}} = 100\Omega \; (5 \; \text{places}), \text{worst-case pattern (Figure 6)}, \\ \textbf{f}_{\text{CLK}} = 135\text{MHz}$ | | | | |
| | | I _(VCC) + I _(PLLVCC) + I _(LVDSVCC) | | 102.2 | | |
| | | I _(IOVCC) with IOVCC = 3.6V | | 2.1 | | mA |
| | | I _(IOVCC) with IOVCC = 1.8V | | 0.8 | | |
| ો | Input capacitance | | | 2 | | рF |

⁽¹⁾ All typical values are at VCC = 3.3V, T_A = 25°C.



SWITCHING CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP ⁽¹⁾ | MAX | UNIT |
|-------------------|---|--|--|--|----------------------------------|------|
| t ₀ | Delay time, CLKOUT↑ after Yn valid (serial bit position 0, equal D1, D9, D20, D5) | | -0.1 | 0 | 0.1 | ns |
| t ₁ | Delay time, CLKOUT↑ after Yn valid (serial bit position 1, equal D0, D8, D19, D27) | | ¹ / ₇ t _c - 0.1 | | $^{1}/_{7} t_{c} + 0.1$ | ns |
| t ₂ | Delay time, CLKOUT↑ after Yn valid (serial bit position 2, equal D7, D18, D26. D23) | See Figure 7, t _C = 10ns, Input clock jitter < 25ps ⁽²⁾ | ² / ₇ t _c - 0.1 | | $^{2}/_{7}$ t _c + 0.1 | ns |
| t ₃ | Delay time, CLKOUT↑ after Yn valid (serial bit position 3; equal D6, D15, D25, D17) | | ³ / ₇ t _c - 0.1 | | $^{3}/_{7} t_{c} + 0.1$ | ns |
| t ₄ | Delay time, CLKOUT↑ after Yn valid (serial bit position 4, equal D4, D14, D24, D16) | | ⁴ / ₇ t _c - 0.1 | | $^{4}/_{7} t_{c} + 0.1$ | ns |
| t ₅ | Delay time, CLKOUT↑ after Yn valid (serial bit position 5, equal D3, D13, D22, D11) | | ⁵ / ₇ t _c - 0.1 | | $^{5}/_{7} t_{c} + 0.1$ | ns |
| t ₆ | Delay time, CLKOUT↑ after Yn valid (serial bit position 6, equal D2, D12, D21, D10) | | ⁶ / ₇ t _c - 0.1 | | $^{6}/_{7} t_{c} + 0.1$ | ns |
| t _{c(o)} | Output clock period | | | t _c | | ns |
| | | t _C = 10ns; clean reference clock, see Figure 8 | | ±26 | | |
| Λt | Output clock cycle-to-cycle jitter (3) | t _C = 10ns with 0.05UI added noise modulated at 3MHz, see Figure 8 | | ±44 | | ps |
| $\Delta t_{c(o)}$ | Output clock cycle-to-cycle jittel | t _C = 7.4ns; clean reference clock, see Figure 8 | | ±35 | | ρs |
| | | t _C = 7.4ns with 0.05UI added noise modulated at 3MHz, see Figure 8 | | ±42 | | |
| t _w | High-level output clock pulse duration | | | ⁴ / ₇ t _c | | ns |
| t _{r/f} | Differential output voltage transition time (t _r or t _f) | See Figure 4 | | 225 | 500 | ps |
| t _{en} | Enable time, SHTDN↑ to phase lock (Yn valid) | f _(clk) = 135MHz, See Figure 9 | | 6 | | μs |
| t _{dis} | Disable time, SHTDN↓ to off-state (CLKOUT high-impedance) | f _(clk) = 135MHz, See Figure 10 | | 7 | | ns |

All typical values are at V_{CC} = 3.3 V, T_A = 25°C. [Input clock jitter] is the magnitude of the change in the input clock period.

THERMAL CHARACTERISTICS

| | PARAMETER | TEST CONDITIONS | | ZQL | | | DGG | | |
|----------------------|--------------------------------------|---|------|------|-----|------|------|------|------|
| | PARAMETER | | | TYP | MAX | MIN | TYP | MAX | UNIT |
| | Junction-to-free-air | Low-K JEDEC test board, 1s (single signal layer), no air flow | | 85 | | | | | |
| θ_{JA} | thermal resistance | High-K JEDEC test board, 2s2p (double signal layer, double buried power plane), no air flow | | 67.1 | | | 63.4 | | °C/W |
| θ_{JC} | Junction-to-case thermal resistance | Cu cold plate measurement process | | 25.2 | | | 15.9 | | °C/W |
| θ_{JB} | Junction-to-board thermal resistance | EIA/JESD 51-8 | 31.0 | | | 32.5 | | °C/W | |
| ΨЈТ | Junction-to-top of package | EIA/JESD 51-2 | | 0.8 | | | 0.4 | | °C/W |

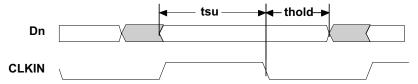
The output clock cycle-to-cycle jitter is the largest recorded change in the output clock period from one cycle to the next cycle observed over 15,000 cycles. Tektronix TDSJIT3 Jitter Analysis software was used to derive the maximum and minimum jitter value.

www.ti.com

THERMAL CHARACTERISTICS (continued)

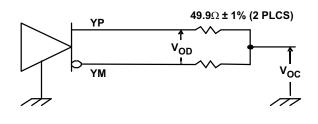
| | PARAMETER | TEST CONDITIONS | ZQL | | | DGG | | | UNIT |
|----------------|-------------------------------------|-----------------|-----|------|-----|-----|------|-----|------|
| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | MIN | TYP | MAX | UNII |
| ΨЈВ | Junction-to-board | EIA/JESD 51-6 | | 30.3 | | | 32.2 | | °C/W |
| T _A | Operating ambient temperature range | | -10 | | 70 | -10 | | 70 | °C |
| TJ | Virtual junction temperature | | 0 | | 105 | 0 | | 105 | °C |

PARAMETER MEASUREMENT INFORMATION



All input timing is defined at IOVDD / 2 on an input signal with a 10% to 90% rise or fall time of less than 3 ns. CLKSEL = 0V.

Figure 3. Set Up and Hold Time Definition



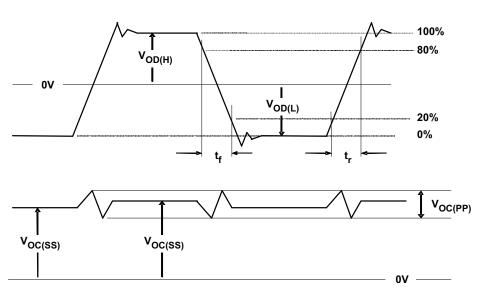
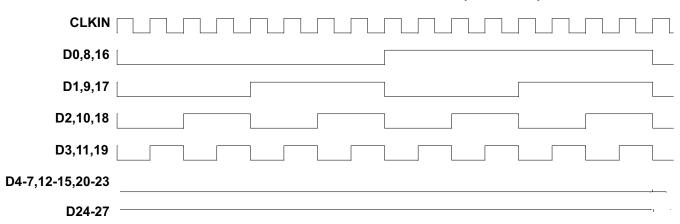


Figure 4. Test Load and Voltage Definitions for LVDS Outputs.

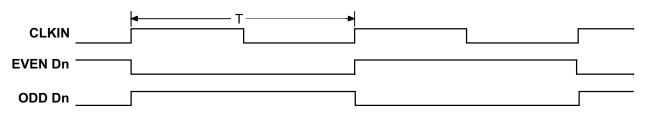


PARAMETER MEASUREMENT INFORMATION (continued)



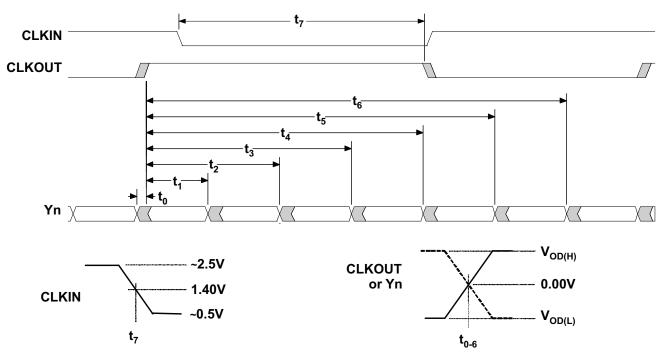
The 16 grayscale test pattern test device power consumption for a typical display pattern.

Figure 5. 16 Grayscale Test Pattern



The worst-case test pattern produces nearly the maximum switching frequency for all of the LVDS outputs.

Figure 6. Worst-Case Power Test Pattern



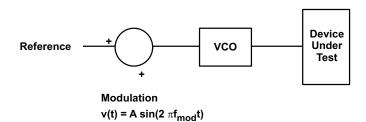
CLKOUT is shown with CLKSEL at high-level. CLKIN polarity depends on CLKSEL input level.

Figure 7. SN75LVDS83B Timing Definitions

CLKOUT



PARAMETER MEASUREMENT INFORMATION (continued)



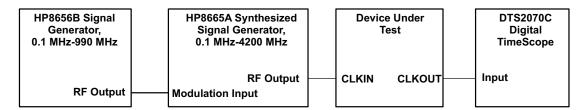


Figure 8. Output Clock Jitter Test Set Up

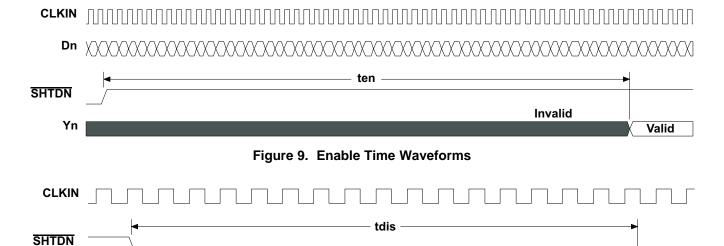
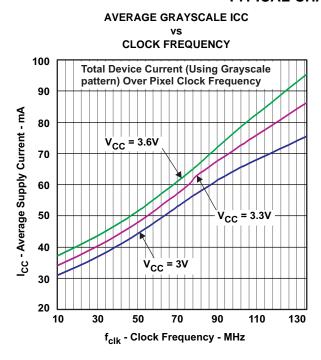


Figure 10. Disable Time Waveforms

10



TYPICAL CHARACTERISTICS



OUTPUT CLOCK JITTER

f_(mod) - Input Modular Frequency - MHz

1

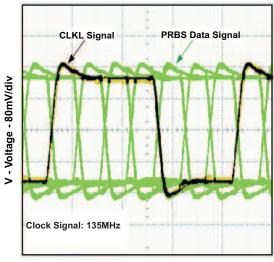
0.10

Figure 11.

Figure 12.

TYPICAL PRBS OUTPUT SIGNAL OVER ONE CLOCK PERIOD

0.01



t_k - Time - 1ns/div Figure 13.



APPLICATION INFORMATION

This section describes the power up sequence, provides information on device connectivity to various GPU and LCD display panels, and offers a pcb routing example.

Power Up Sequence

The SN75LVDS83B does not require a specific power up sequence.

It is permitted to power up IOVCC while VCC, VCCPLL, and VCCLVDS remain powered down and connected to GND. The input level of the SHTDN during this time does not matter as only the input stage is powered up while all other device blocks are still powered down.

It is also permitted to power up all 3.3V power domains while IOVCC is still powered down to GND. The device will not suffer damage. However, in this case, all the I/Os are detected as logic HIGH, regardless of their true input voltage level. Hence, connecting SHTDN to GND will still be interpreted as a logic HIGH; the LVDS output stage will turn on. The power consumption in this condition is significantly higher than standby mode, but still lower than normal mode.

The user experience can be impacted by the way a system powers up and powers down an LCD screen. The following sequence is recommended:

Power up sequence (SN75LVDS83B SHTDN input initially low):

- 1. Ramp up LCD power (maybe 0.5ms to 10ms) but keep backlight turned off.
- 2. Wait for additional 0-200ms to ensure display noise won't occur.
- 3. Enable video source output; start sending black video data.
- 4. Toggle LVDS83B shutdown to $\overline{SHTDN} = V_{IH}$.
- Send >1ms of black video data; this allows the LVDS83B to be phase locked, and the display to show black data first.
- 6. Start sending true image data.
- 7. Enable backlight.

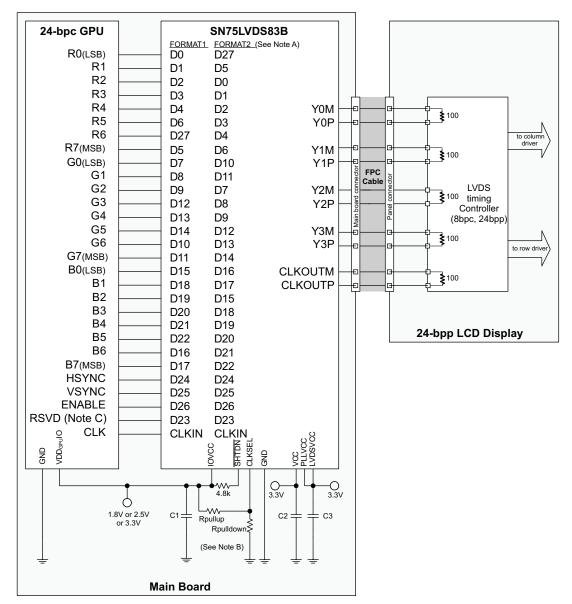
Power Down sequence (SN75LVDS83B SHTDN input initially high):

- 1. Disable LCD backlight; wait for the minimum time specified in the LCD data sheet for the backlight to go low.
- 2. Video source output data switch from active video data to black image data (all visible pixel turn black); drive this for >2 frame times.
- 3. Set SN75LVDS83B input SHTDN = GND; wait for 250ns.
- 4. Disable the video output of the video source.
- 5. Remove power from the LCD panel for lowest system power.

Signal Connectivity

While there is no formal industry standardized specification for the input interface of LVDS LCD panels, the industry has aligned over the years on a certain data format (bit order). Figure 14 through Figure 17 show how each signal should be connected from the graphic source through the SN75LVDS83B input, output and LVDS LCD panel input. Detailed notes are provided with each figure.





Note A. **FORMAT**: The majority of 24-bit LCD display panels require the two most significant bits (2 MSB) of each color to be transferred over the 4th serial data output Y3. A few 24-bit LCD display panels require the two LSBs of each color to be transmitted over the Y3 output. The system designer needs to verify which format is expected by checking the LCD display data sheet.

- Format 1: use with displays expecting the 2 MSB to be transmitted over the 4th data channel Y3. This is the dominate data format for LCD panels.
- Format 2: use with displays expecting the 2 LSB to be transmitted over the 4th data channel.

Note B. **Rpullup**: install only to use rising edge triggered clocking. **Rpulldown**: install only to use falling edge triggered clocking.

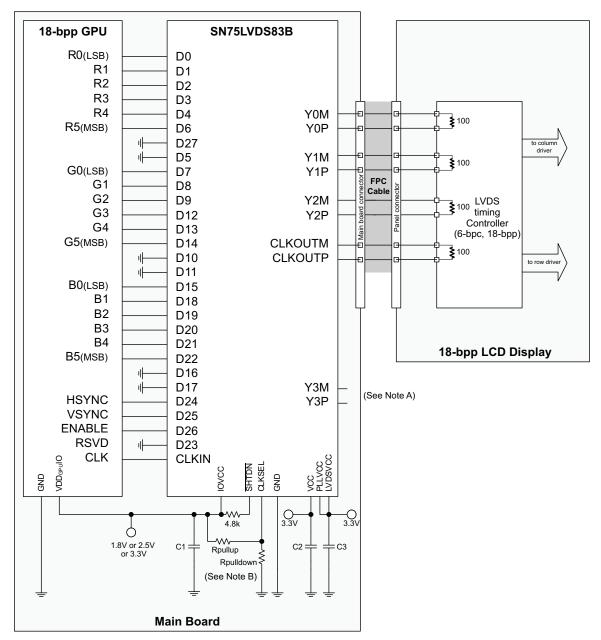
- C1: decoupling cap for the VDDIO supply; install at least 1x0.01µF.
- C2: decoupling cap for the VDD supply; install at least 1x0.1μF and 1x0.01μF.
- C3: decoupling cap for the VDDPLL and VDDLVDS supply; install at least 1x0.1μF and 1x0.01μF.

Note C. If RSVD is not driven to a valid logic level, then an external connection to GND is recommended.

Note D. RSVD must be driven to a valid logic level. All unused SN75LVDS83B inputs must be tied to a valid logic level.

Figure 14. 24-Bit Color Host to 24-bit LCD Panel Application





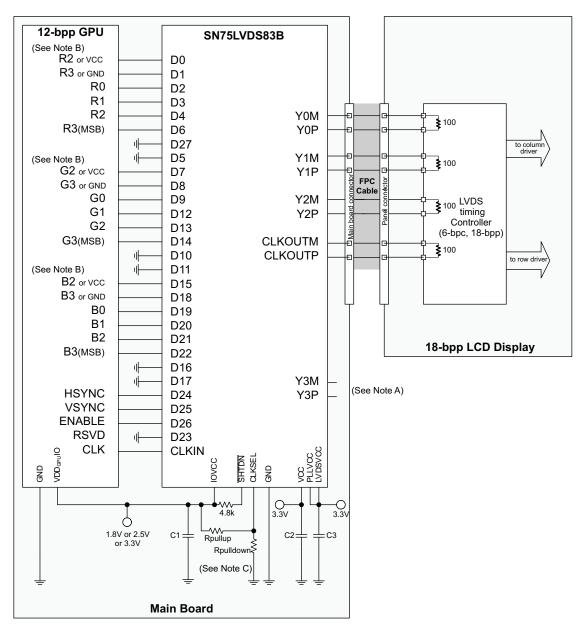
Note A. Leave output Y3 NC.

Note B.Rpullup: install only to use rising edge triggered clocking. Rpulldown: install only to use falling edge triggered clocking.

- C1: decoupling cap for the VDDIO supply; install at least 1x0.01μF.
- C2: decoupling cap for the VDD supply; install at least 1x0.1µF and 1x0.01µF.
- C3: decoupling cap for the VDDPLL and VDDLVDS supply; install at least 1x0.1μF and 1x0.01μF.

Figure 15. 18-Bit Color Host to 18-Bit Color LCD Panel Display Application





Note A. Leave output Y3 N.C.

Note B. **R3**, **G3**, **B3**: this MSB of each color also connects to the 5th bit of each color for increased dynamic range of the entire color space at the expense of none-linear step sizes between each step. For linear steps with less dynamic range, connect D1, D8, and D18 to GND.

R2, G2, B2: these outputs also connects to the LSB of each color for increased, dynamic range of the entire color space at the expense of none-linear step sizes between each step. For linear steps with less dynamic range, connect D0, D7, and D15 to VCC.

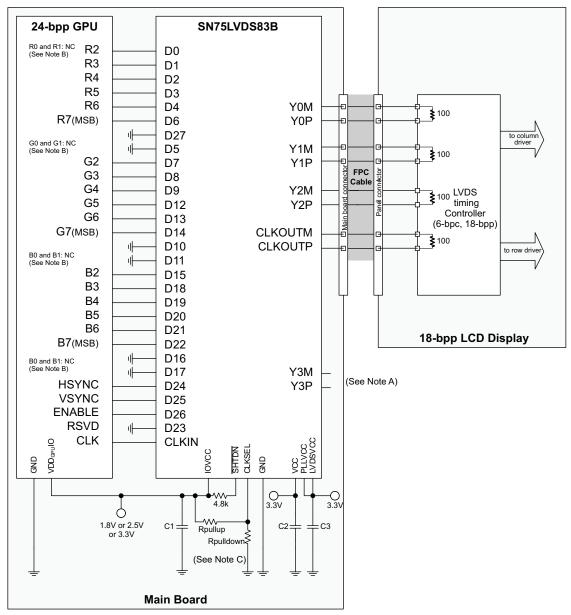
Note C.Rpullup: install only to use rising edge triggered clocking.

Rpulldown: install only to use falling edge triggered clocking.

- C1: decoupling cap for the VDDIO supply; install at least 1x0.01µF.
- C2: decoupling cap for the VDD supply; install at least $1x0.1\mu F$ and $1x0.01\mu F$.
- C3: decoupling cap for the VDDPLL and VDDLVDS supply; install at least 1x0.1µF and 1x0.01µF.

Figure 16. 12-Bit Color Host to 18-Bit Color LCD Panel Display Application





Note A. Leave output Y3 NC.

Note B. R0, R1, G0, G1, B0, B1: For improved image quality, the GPU should dither the 24-bit output pixel down to18-bit per pixel.

NoteC.Rpullup: install only to use rising edge triggered clocking.

Rpulldown: install only to use falling edge triggered clocking.

- C1: decoupling cap for the VDDIO supply; install at least 1x0.01µF.
- C2: decoupling cap for the VDD supply; install at least 1x0.1µF and 1x0.01µF.
- C3: decoupling cap for the VDDPLL and VDDLVDS supply; install at least 1x0.1µF and 1x0.01µF.

Figure 17. 24-Bit Color Host to 18-Bit Color LCD Panel Display Application



Typical Application Schematic

Figure 18 represents the schematic drawing of the SN75LVDS83B evaluation module.

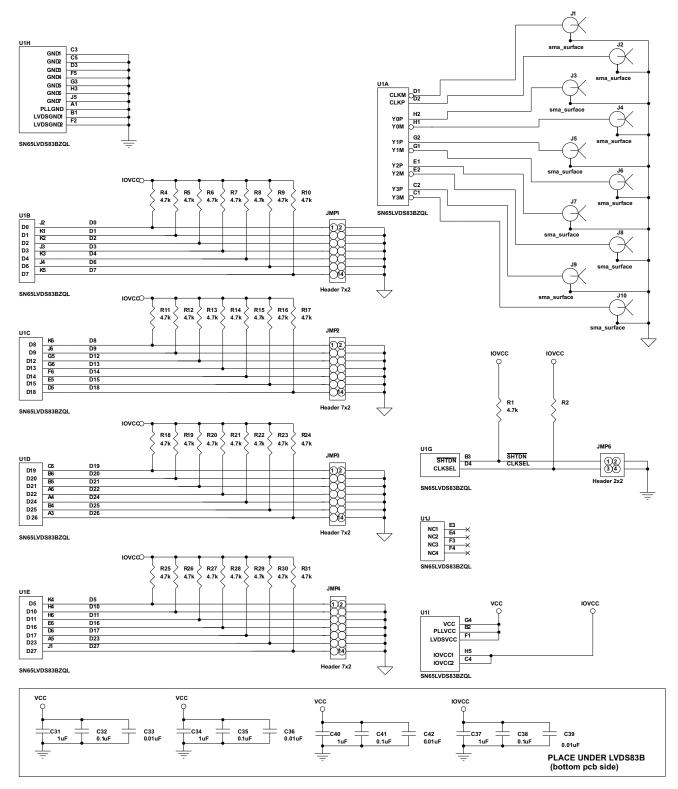


Figure 18. Schematic Example (SN75LVDS83B Evaluation Board)



PCB Routing

Figure 19 and Figure 20 show a possible breakout of the data input and output signals from the BGA package.

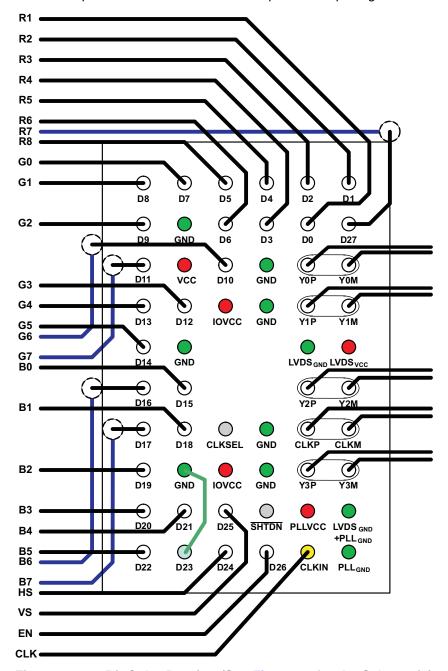


Figure 19. 24-Bit Color Routing (See Figure 14 for the Schematic)



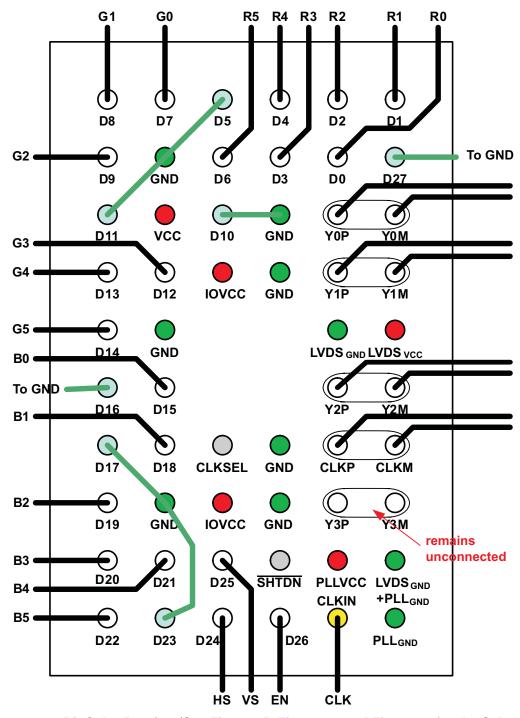


Figure 20. 18-Bit Color Routing (See Figure 15, Figure 16, and Figure 17 for the Schematic)





REVISION HISTORY

| Changes from Original (May 2009) to Revision A | Page |
|---|------|
| Changed text and replaced TBDs in Note A and Note B of Figure 14 | 16 |
| Changed Note B of Figure 15 - Replaced TBDs. | 17 |
| Changed Note B of Figure 16 - Replaced TBDs. | 18 |
| Changed Note C of Figure 17 - Replaced TBDs. | 19 |
| Changed Figure 19 - removed 3 GND pin locations. | 21 |
| Changed Figure 20 - removed 3 GND pin locations. | 22 |
| Changes from Revision A (October 2009) to Revision B | Page |
| Added Storage temperature, T _s to ABSOLUTE MAXIMUM RATINGS | 2 |
| Added Note 3 to DISSIPATION RATINGS | 3 |
| Deleted max values for Supply current (average) | g |
| Changed Enable time units from ns to μs | 1C |
| Added Thermal Characteristics table | 10 |
| Changed G7(LSB) to G7(MSB) in Figure 14 | 16 |
| Added Note C to Figure 14 | 16 |
| Added Note D to Figure 14 | 16 |
| Added connection between GND and D23 to Figure 19 | 21 |





www.ti.com 24-Jan-2013

PACKAGING INFORMATION

| Orderable Device | Status | Package Type | _ | | Package Qty | Eco Plan | Lead/Ball Finish | MSL Peak Temp | Op Temp (°C) | Top-Side Markings | Samples |
|------------------|--------|----------------------------|---------|----|-------------|----------------------------|------------------|---------------------|--------------|-------------------|---------|
| | (1) | | Drawing | | | (2) | | (3) | | (4) | |
| SN75LVDS83BDGG | ACTIVE | TSSOP | DGG | 56 | 35 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-2-260C-1 YEAR | -10 to 70 | LVDS83B | Samples |
| SN75LVDS83BDGGR | ACTIVE | TSSOP | DGG | 56 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-2-260C-1 YEAR | -10 to 70 | LVDS83B | Samples |
| SN75LVDS83BZQLR | ACTIVE | BGA MICROSTAR JUNIOR | ZQL | 56 | 1000 | Green (RoHS & no Sb/Br) | SNAGCU | Level-2-260C-1 YEAR | -10 to 70 | LVDS83B | Samples |

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ Only one of markings shown within the brackets will appear on the physical device.

PACKAGE MATERIALS INFORMATION

www.ti.com 26-Mar-2013

TAPE AND REEL INFORMATION





| | Dimension designed to accommodate the component width |
|----|---|
| B0 | Dimension designed to accommodate the component length |
| K0 | Dimension designed to accommodate the component thickness |
| W | Overall width of the carrier tape |
| P1 | Pitch between successive cavity centers |

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

| Device | Package Type | Package Drawing | | SPQ | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|-----------------|----------------------------------|--------------------|----|------|--------------------------|--------------------------|------------|------------|------------|------------|-----------|------------------|
| SN75LVDS83BZQLR | BGA MI CROSTA R JUNI OR | ZQL | 56 | 1000 | 330.0 | 16.4 | 4.8 | 7.3 | 1.5 | 8.0 | 16.0 | Q1 |

PACKAGE MATERIALS INFORMATION

www.ti.com 26-Mar-2013



*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
|-----------------|-------------------------|-----------------|------|------|-------------|------------|-------------|
| SN75LVDS83BZQLR | BGA MICROSTAR JUNIOR | ZQL | 56 | 1000 | 336.6 | 336.6 | 28.6 |

ZQL (R-PBGA-N56)

PLASTIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-285 variation BA-2.
- D. This package is Pb-free. Refer to the 56 GQL package (drawing 4200583) for tin-lead (SnPb).

MicroStar Junior is a trademark of Texas Instruments



DGG (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

48 PINS SHOWN



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

Products Applications

Audio www.ti.com/audio Automotive and Transportation www.ti.com/automotive Communications and Telecom **Amplifiers** amplifier.ti.com www.ti.com/communications **Data Converters** dataconverter.ti.com Computers and Peripherals www.ti.com/computers **DLP® Products** www.dlp.com Consumer Electronics www.ti.com/consumer-apps

DSP **Energy and Lighting** dsp.ti.com www.ti.com/energy Clocks and Timers www.ti.com/clocks Industrial www.ti.com/industrial Interface interface.ti.com Medical www.ti.com/medical logic.ti.com Logic Security www.ti.com/security

Power Mgmt power.ti.com Space, Avionics and Defense www.ti.com/space-avionics-defense

Microcontrollers microcontroller.ti.com Video and Imaging www.ti.com/video

RFID www.ti-rfid.com

OMAP Applications Processors www.ti.com/omap TI E2E Community e2e.ti.com

Wireless Connectivity <u>www.ti.com/wirelessconnectivity</u>